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- Functionally Equivalent to AMD's AM29823
- Provide Extra Data Width Necessary for Wider Address/Data Paths or Buses With **Parity**
- **Outputs Have Undershoot-Protection** Circuitry
- Power-Up High-Impedance State
- Buffered Control Inputs Reduce dc Loading **Effects**
- Package Options Include Plastic Small-Outline (DW) Packages and Standard Plastic (NT) and Ceramic (JT) 300-mil DIPs

24 🛮 V_{CC} 1D 🛮 2 23 🛮 1Q 22 1 2Q 2D 🛮 3 3D 🛮 4 21 3Q 4D ∏5 20 4Q 5D ∏6 19 **∏** 5Q 6D **∏**7 18**∏** 6Q 7D 🛮 8 17 7Q 8D []9 16∏8Q 9D **∏**10 15∏9Q 14 CLKEN CLR [] 11

13 CLK

SN54ALS29823 . . . JT PACKAGE

SN74ALS29823 . . . DW OR NT PACKAGE

(TOP VIEW)

OE

GND Π_{12}

description

These 9-bit flip-flops feature 3-state outputs designed specifically for driving highly capacitive

or relatively low-impedance loads. They are particularly suitable for implementing wider buffer registers, I/O ports, bidirectional bus drivers, parity bus interfacing, and working registers.

With the clock-enable (CLKEN) input low, the nine D-type edge-triggered flip-flops enter data on the low-to-high transitions of the clock (CLK) input. Taking CLKEN high disables the clock buffer, latching the outputs. The 'ALS29823 have noninverting data (D) inputs. Taking the clear (CLR) input low causes the nine Q outputs to go low independently of the clock.

A buffered output-enable (\overline{OE}) input places the nine outputs in either a normal logic state (high or low logic levels) or a high-impedance state. The outputs also are in the high-impedance state during power-up and power-down conditions. The outputs remain in the high-impedance state while the device is powered down. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

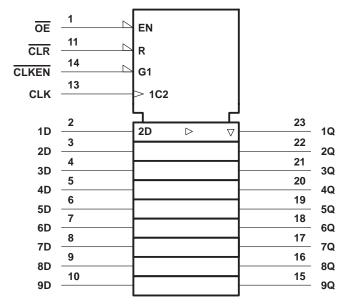
OE does not affect the internal operation of the flip-flops. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ALS29823 is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS29823 is characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each flip-flop)

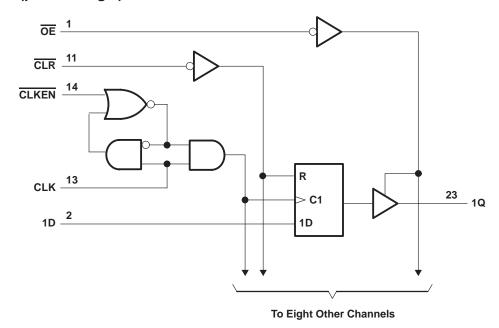
	INPUTS				
OE	CLR	CLKEN	CLK	D	Q
L	L	Х	Χ	Х	L
L	Н	L	\uparrow	Н	Н
L	Н	L	\uparrow	L	L
L	Н	Н	Χ	Χ	Q ₀
Н	Χ	Χ	Χ	Х	Z

logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)





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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V _{CC}		7 ∨
Input voltage, V _I		5.5 V
Voltage applied to a disabled high-impedance output		5.5 V
Operating free-air temperature range, T _A : SN54ALS29823	−55°C to	125°C
Storage temperature range	−65°C to	150°C

recommended operating conditions

					SN54ALS29823		
			MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		4.5	5	5.5	V	
VIH	High-level input voltage		2			V	
VIL	Low-level input voltage				0.8	V	
lOH	High-level output current				-18	mA	
loL	Low-level output current				32	mA	
	Pulse duration	CLR low	7			ns	
t _W	Fuise duration	CLK high or low	8			113	
	Setup time before CLK↑	CLR inactive	7				
t _{su}		Data	4			ns	
		CLKEN high or low	8				
th	Hold fine offer OLIVA	CLKEN	2			ns	
	Hold time after CLK↑	Data	4			115	
TA	Operating free-air temperature		-55	25	125	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED			SN5	4ALS29	823	LINIT
PARAMETER	TEST CO	TEST CONDITIONS		TYP [‡]	MAX	UNIT
VIK	$V_{CC} = 4.5 \text{ V},$	$I_{I} = -18 \text{ mA}$			-1.2	V
Vali	V _{OH} V _{CC} = 4.5 V	$I_{OH} = -12 \text{ mA}$	2.4	3.3		V
VOH	∨CC = 4.5 ∨	$I_{OH} = -18 \text{ mA}$	2			٧
V _{OL}	$V_{CC} = 4.5 \text{ V},$	$I_{OL} = 32 \text{ mA}$		0.25	0.5	V
ГОΖН	$V_{CC} = 5.5 \text{ V},$	V _O = 2.4 V			50	μΑ
lozL	$V_{CC} = 5.5 \text{ V},$	V _O = 0.4 V			-50	μΑ
ΙĮ	$V_{CC} = 5.5 \text{ V},$	V _I = 5.5 V			0.1	mA
lін	$V_{CC} = 5.5 \text{ V},$	V _I = 2.7 V			20	μΑ
Ι _{ΙL}	$V_{CC} = 5.5 \text{ V},$	$V_{I} = 0.4 V$			-0.5	mA
IOS§	$V_{CC} = 5.5 V$,	V _O = 0	-75		-250	mA
		Outputs high			90	
lcc	$V_{CC} = 5.5 \text{ V}$	Outputs low			105	mA
		Outputs open			115	

[‡] All typical values are at $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

[§] Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.



[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

SN54ALS29823, SN74ALS29823 9-BIT BUS-INTÉRFACE FLIP-FLOPS WITH 3-STATE OUTPUTS

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switching characteristics (see Figure 1)

	FROM	TO (OUTPUT)		V _{CC} = MIN T _A = MIN t	UNIT	
PARAMETER	(INPUT)		TEST CONDITIONS	SN54AL		
				MIN	MAX	
^t PLH	CLK	A O	0 50 - 5	2	11.5	ns
^t PHL	CLK	Any Q	C _L = 50 pF	2	11.5	115
^t PLH	CLK	A O	C. 200 = E	2	21	ns
^t PHL	CLK	Any Q	C _L = 300 pF	2	21	115
^t PHL	CLR	Any Q	C _L = 50 pF	1	17.5	ns
^t PZH		A O	C _L = 50 pF	1	17	ns
^t PZL	ŌĒ	Any Q		1	17	
^t PZH	ŌĒ	A O	0 200 = 5	1	25	
^t PZL	OE	Any Q	C _L = 300 pF	1	29.5	ns
^t PHZ	ŌĒ	A O	0. 50	1	16	ns
tPLZ	OE	Any Q	C _L = 50 pF	1	14	115
^t PHZ	ŌĒ	Any Q	C _L = 5 pF	1	12	ns
^t PLZ	OL	Ally Q	O[= 3 μr	1	11	115

T For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V _{CC}	7 V
Input voltage, V _I	5.5 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T _A : SN74ALS29823	0°C to 70°C
Storage temperature range	-65°C to 150°C

[‡] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

				SN74ALS29823			LINUT	
				MIN	NOM	MAX	UNIT	
Vcc	Supply voltage			4.75	5	5.25	V	
VIH	High-level input voltage			2			V	
V _{IL}	Low-level input voltage					0.8	V	
loH	High-level output current					-24	mA	
loL	Low-level output current					48	mA	
	Pulse duration		CLR low	5			ns	
t _W	ruise duration	CLK high or low	5			115		
	Setup time before CLK↑		CLR inactive	5				
t _{su}			Data	2			ns	
		CLKEN high or low	6					
th	Hold fire a often CLIV [↑]		CLKEN	0			ns	
	Hold time after CLK↑		Data	2			115	
TA	Operating free-air temperature		_	0	25	70	°C	



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER			SN7	4ALS29	823	UNIT
PARAMETER	PARAMETER TEST CONDITIONS		MIN	TYP†	MAX	UNII
VIK	$V_{CC} = 4.75 V,$	$I_1 = -18 \text{ mA}$			-1.2	V
Vari	Vac = 4.75 V	$I_{OH} = -15 \text{ mA}$	2.4	3.3		V
VOH	V _{CC} = 4.75 V	$I_{OH} = -24 \text{ mA}$	2	3.1		v
V _{OL}	$V_{CC} = 4.75 V,$	$I_{OL} = 48 \text{ mA}$		0.35	0.5	V
lozh	$V_{CC} = 5.25 \text{ V},$	$V_0 = 2.4 \text{ V}$			20	μΑ
lozL	$V_{CC} = 5.25 \text{ V},$	V _O = 0.4 V			-20	μΑ
IĮ	V _{CC} = 5.25 V,	V _I = 5.5 V			0.1	mA
IIH	V _{CC} = 5.25 V,	V _I = 2.7 V			20	μΑ
IIL	V _{CC} = 5.25 V,	V _I = 0.4 V			-0.2	mA
los [‡]	V _{CC} = 5.25 V,	V _O = 0	-75		-250	mA
Icc	V _{CC} = 5.25 V,	Outputs open		80	115	mA

switching characteristics (see Figure 1)

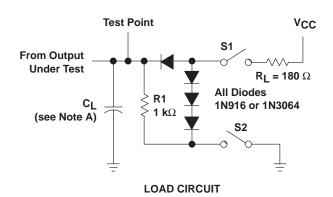
	FROM	то		V _{CC} = MIN T _A = MIN to	UNIT		
PARAMETER	(INPUT)	(OUTPUT)	TEST CONDITIONS	SN74AL			
				MIN	MAX		
^t PLH	CLK	A O	0. 50.55	2	10	ns	
t _{PHL}	OLK	Any Q	C _L = 50 pF	2	10	115	
t _{PLH}	CLK	A 0	0 000 = 5		16	ns	
t _{PHL}	CLK	Any Q	C _L = 300 pF		16		
t _{PHL}	CLR	Any Q	C _L = 50 pF		12	ns	
^t PZH	ŌĒ	Any Q	C _L = 50 pF		14	ns	
tpzL	OE				14		
^t PZH	ŌĒ	A O	0 000 - 5		20	no	
tPZL	OE	Any Q	C _L = 300 pF		23	ns	
t _{PHZ}	ŌĒ	A O	0 50 - 5		14	no	
tpLZ	OE	Any Q	C _L = 50 pF		12	ns	
^t PHZ	ŌĒ	Any Q	C: - 5 pE		9	no	
t _{PLZ}	OE .	Ally Q	$C_L = 5 pF$		9	ns	

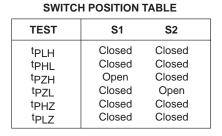
[§] For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

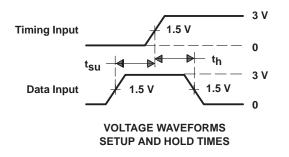


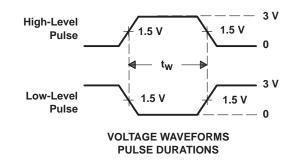
[†] All typical values are at V_{CC} = 5 V, T_A = 25°C. ‡ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

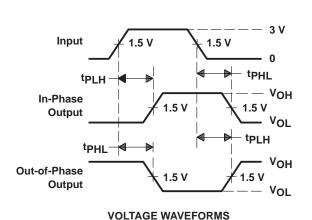
PARAMETER MEASUREMENT INFORMATION



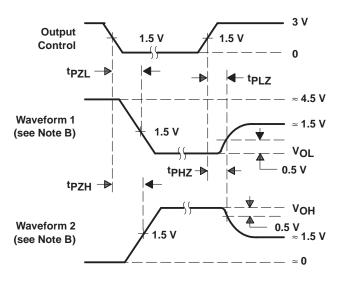








PROPAGATION DELAY TIMES



VOLTAGE WAVEFORMS ENABLE AND DISABLE TIMES, 3-STATE OUTPUTS

- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq 2.5$ ns. $t_f \leq 2.5$ ns.

Figure 1. Load Circuit and Voltage Waveforms



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